

Search Notes

Application/Control No.

10/542,394

Examiner

Tran N. Nguyen

Applicant(s)/Patent under Reexamination

FUJITA, KATSUFUSA

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	216 217 254 261	7/1/06	<i>[Signature]</i>
336	210 212 219 234	7/4/06	<i>[Signature]</i>
update all above		12/12/06	<i>[Signature]</i>
update all above		6/19/07	<i>[Signature]</i>
update all above		10/23/07	<i>[Signature]</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
310	all of	10/23/07	<i>[Signature]</i>
336	above		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Interference Search	10/23/07	<i>[Signature]</i>